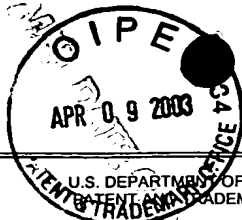


# 4 S.W.H. 6/26/02

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 196880US2 SRD		SERIAL NO. 09/652,010	
<div style="border: 2px solid black; border-radius: 50%; padding: 10px; display: inline-block;"><div style="text-align: center;">U.S. P. JUN 21 2002</div></div> <div style="text-align: center; margin-top: 5px;">LIST OF REFERENCES CITED BY APPLICANT</div>				APPLICANT Katsuyuki NAITO et al.			
				FILING DATE 08/31/00		GROUP <del>8664</del> 2653	
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
BV	AA	6,197,399	03/06/01	NAITO et al.	—	—	
BV	AB	6,125,095	09/26/00	GEMMA et al.	—	—	
	AC						
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<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AO						
	AP						
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	AR						
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	AV						
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
	AW						
	AX						
	AY						
	AZ						
Examiner <i>Bach Veong</i>					Date Considered 11/13/03		
<small>*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

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ATTY DOCKET NO.

196880US2SRD

SERIAL NO.

09/652,010

## LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Katsuyuki NAITO, et al.

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
BV	AA	5,027,216	06/25/91	I. TAKANASHI, et al.			
RV	AB	3,801,966	04/02/74	M. TERA0			
RV	AC	4,956,714	09/11/90	I. TAKANASHI, et al.			
RV	AD	5,162,819	11/10/92	K. SAKAI, et al.			
RV	AE	5,479,384	12/26/95	P. TOTH, et al.			
BV	AF	5,270,995	12/14/93	K. WADA, et al.			
RV	AG	4,701,880	10/20/87	K. ICHIHARA			
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## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
RV	AO	57-123541	08/02/82	JAPAN (with English Abstract)		X
RV	AP	10-172166	06/26/98	JAPAN (with English Abstract)		X
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

BV	AW	Patent Abstracts of Japan, JP 60-212843, October 25, 1985
RV	AX	Patent Abstracts of Japan, JP 57-135445, August 21, 1982
RV	AY	Patent Abstracts of Japan, JP 10-289496, October 27, 1998
	AZ	

☐ Additional References sheet(s) attached

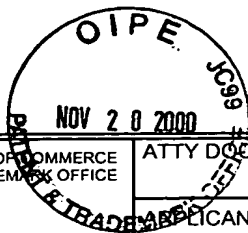
Examiner

Bach Vuong

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
BV	AA	5,675,532	10/07/97	N. GEMMA, et al.	—	—	
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		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO	
BV	AO	2-125264	05/14/90	JAPAN (with English Abstract)		X
BV	AP	2-127649	05/16/90	JAPAN (with English Abstract)		X
BV	AQ	2-250473	10/08/90	JAPAN (with English Abstract)		X
BV	AR	8-045122	02/16/96	JAPAN (with English Abstract)		X
BV	AS	7-254153	10/03/95	JAPAN (with English Abstract)		X
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BV	AW	C. LIU, et al., Science, Vol. 261, pps. 897-899, "HIGH-DENSITY NANOSECOND CHARGE TRAPPING IN THIN FILMS OF THE PHOTOCONDUCTOR ZnODEP," August 13, 1993
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BV	AY	S. HOSAKA, et al., Thin Solid Films, Vol. 273, pps. 122-127, "SCANNING NEAR-FIELD OPTICAL MICROSCOPE WITH A LASER DIODE AND NANOMETER-SIZED BIT RECORDING," 1996
BV	AZ	S. HOSAKA, et al., J. Appl. Phys., Vol. 79, No. 10, pps. 8082-8086, "PHASE CHANGE RECORDING USING A SCANNING NEAR-FIELD OPTICAL MICROSCOPE," May 15, 1996

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